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Authors

Sun, Yanxiao Jiang, Luyue Wang, Zhe <u>et al.</u>

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5	Photodetectors Based on Hybrid Systems Combining Two-dimensional materials and
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8	Yanxiao Sun ¹ , Gang Niu ¹ *, Wei Ren ¹ , Xiangjian Meng ² , Jinyan Zhao ¹ , Wenbo Luo ³ , Zuo-
9	Guang Ye ⁴ , Ya-Hong Xie ⁵
10	
11	1. Electronic Materials Research Laboratory, Key Laboratory of the Ministry of
12	Education & International Center for Dielectric Research, School of Electronic Science
13	and Engineering, Xi'an Jiaotong University, No. 28, Xianning West Road, Xi'an, Shaanxi,
14	710049, P.R. China
15	E-mail: <u>gangniu@xjtu.edu.cn</u>
16	2. National Laboratory for Infrared Physics, Shanghai Institute of Technical Physics,
17	Chinese Academy of Sciences, Shanghai, China
18	3. State Key Laboratory of Electronic Thin Films and Integrated Devices, University of
19	Electronic Science and Technology of China, Chengdu, 611731 China
20	4. Department of Chemistry and 4D LABS, Simon Fraser University, Burnaby, British
21	Columbia, V5A 1S6, Canada
22	5. Department of Materials Science and Engineering, University of California, Los
23	Angeles, Los Angeles, California, United States
24	
25	
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1

27 Two-dimensional materials have been extensively studied in last decades due to their 28 remarkable physical, electrical and optoelectronic properties. Meanwhile, combination of 29 two-dimensional materials with traditional functional materials have provided new approach 30 in a variety of research and application areas. In this review, we have focused on the twodimensional and ferroelectric hybrid system being applied in photodetection. Fundamentals of 31 32 the materials and interaction in the hybrid system was introduced. Modulation of the 33 optoelectronic properties induced by ferroelectricity was discussed in the hybrid system. After 34 introducing the basics of photodetection, the devices were categorized and reviewed based on 35 their structures. Modulation and enhancement of the photodetectors were observed with 36 ferroelectric polarization. Finally, the challenges and perspectives of the photodetectors based 37 on two-dimensional materials and ferroelectrics have been proposed.

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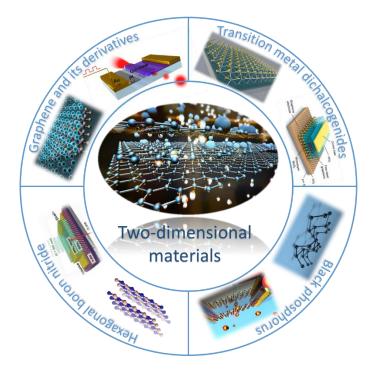
39 **1. Introduction**

40 Last decades have witnessed rapid development of photonic and optoelectronic devices which 41 demonstrate a wide spectrum of applications including photo-emission (eg. photodiodes[1, 2, 42 3, 4], LEDs[5, 6] and lasers[7, 8]), photodetection[9, 10, 11, 12, 13], data storage[14, 15] and energy storage[16, 17]. Nowadays, the information society featuring "Internet of Things" and 43 "big data" demands further evolution of electronics and optoelectronics, particularly for 44 45 telecommunication and communication. Photodetectors, serving as the receiving end, are one 46 of the most important components in such optic communication network. [18] Photodetectors 47 are among the most ubiquitous devices with superiorities of the sufficiently fast response, the 48 high detectivity, the remarkable data storage capability etc. Photodetectors detect light in a 49 certain range of frequency band and the device performance can be evaluated by a series of 50 figures of merit, which are dominated by the device structure and more importantly by 51 detecting materials. Among the massive materials and devices applied in the photodetection, 52 semiconductor-based photodetectors have attracted intense interest from both academic and

industrial fields, thanks to their smaller size, wide band detection and Si-technology compatibility. These photodetectors could be tailored by simply altering the composition of the various layers forming the structure. Both individual devices and the component in the communication system requires compact structure, ultra-thin devices and further optimization of the opto-electronic properties, which has triggered the flourishing of novel materials with outstanding structure and properties.

59 Conventional materials applied in electronic and optoelectronic semiconductor devices are crystalline silicon (Si) and germanium (Ge). Compounds of III-V semiconductors such as 60 Gallium (Ga), Indium (In), Arsenic (As), Phosphorus (P) and antimony (Sb) are also applied 61 62 in the materials as well as the alloys due to their direct bandgap property and have been intensively studied for years.[19, 20, 21] More recently, with the advent of two-dimensional 63 64 (2D) materials, [22, 23] various new photodetection phenomenon have been reported due to 65 their mechanical, thermal, electrical, optical and optoelectronic properties distinguished from that of the three-dimensional counterparts, [24, 25, 26] which has made a tremendous 66 67 progress of photodetectors. Materials with Van der Waals bonds interlayers usually form thick bulk or crystals which makes them difficult utilized in nanodevices. Such obstacle was 68 overcome by the Novoselov and Geim in 2004, who successfully exfoliated the graphene 69 70 nano flake and applied it in a field-effect transistor (FET) for ultrafast photodetection.[27, 28] 71 Since then, 2D materials have rapidly been established as building blocks for photodetectors 72 due to their remarkable optical and optoelectronic properties.[29, 30, 31] Fabrication 73 procedure of 2D materials photodetectors is quite simple, which as well provides a facile 74 platform for micro- and nano- devices fabrication.[32, 33] In general, 2D materials are 75 potential in building highly integrated and efficient photodetectors, and promising candidate 76 for the future integrated optoelectronic devices as well.

The library of 2D materials has experienced a gradual expansion from graphene to its
derivatives (eg. graphene, carbon nano tubes (CNTs), hexagonal boron nitride (h-BN), and to



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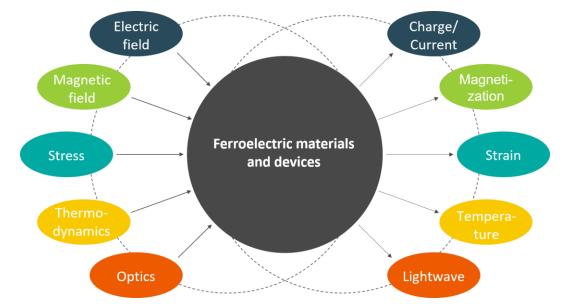
Figure 1. Categories of 2D materials and their applications in electronics and optoelectronics.
 ^[34, 35, 36] Copyright Year, Publisher.

82 layered group-IV and group-III metal chalcogenides, as well as to layered transition metal 83 dichalcogenides (TMDs) with their alloys and heterostructures and other novel functional 84 materials etc., as summarized in Figure 1.[34, 35, 36] With the growth of 2D materials family, they have covered from metal, semiconductor to insulators now. 2D materials have ultra-thin 85 86 physical structure ranging from ~ 0.4 nm (one monolayer) to bulk materials with tens of 87 nanometers. Some 2D materials, like graphene and TMDs, show a typical bandgap transition 88 with the thickness variation, which provide opportunities for bandgap modulation. [37] Meanwhile, Electrical and optoelectronic properties of the 2D materials are closely related to 89 90 the band structure, which corresponding to the thickness variation and bandgap modulation in 91 2D materials.[38] Furthermore, The atomic-scale thickness of 2D materials leads to the high 92 transparency and flexibility, which is of particular interest in novel wearable, flexible and 93 portable devices.

94 Meanwhile, another category of materials being employed in electronic and optoelectronic devices are functional materials, also known as "smart materials", with typical properties 95 responding to the external stimuli. [39] Functional materials are capable of coupling the input 96 97 (eg. electric field, magnetic field, stress, light field and heat) and output (eg. charge/current, 98 magnetization, strain, light and temperature), as shown in Figure 2.[40] The "smart materials" 99 nowadays are widely applied in actuators, sensors and detectors. Among smart materials, 100 ferroelectrics is unique due to its spontaneous reversal of polarization with switching of 101 external electric field. Main application areas of ferroelectrics include energy harvesting, 102 memory devices and data storage devices.[41, 42, 43, 44]. More and more electronic devices 103 and photodetectors with profound performances are achieved with ferroelectric materials 104 employed. [45]

105 Photodetection could be realized with ferroelectrics as active layers, where polarization of the 106 materials could be altered by the incident light, resulted in linear, nonlinear optical or 107 electrical output. Furthermore, polarization of the ferroelectrics enables wavelengths 108 modulation by altering of the applied polarization direction. Both inorganic ferroelectric 109 materials like Pb(Zr,Ti)O₃ (PZT),[46, 47, 48, 49] BaTiO₃ (BTO),[50, 51] LiNbO₃ (LN),[52, 110 53] BiFeO₃ (BFO)[54, 55, 56] and organic compounds PVDF as well as the derivatives[57, 111 58]have been studied and applied in photodetectors. Nevertheless, ferroelectrics can only 112 response to limited frequency band width of light, for other incident light to which 113 ferroelectrics are unable to response, other group of the materials could be introduced. 2D 114 materials, which are known for their wide band response could combine with ferroelectric 115 layers. Such hybrid photodetection systems might probably lead to new phenomena and 116 therefore become a topic attracting increasing studies. As for the photodetectors, the hybrid 117 structure could modulate the carriers and performance of the devices could be optimized. 118 In addition to the materials chosen in photodetection, structure of the devices is also of vital

119 importance. Grouped by structures, photodetectors include devices like phototubes,



121 **Figure 2.** Coupling of the fields in ferroelectric materials and devices

120

photomultipliers and semiconductor photodetectors. Phototubes and photomultipliers are mostly applied as dependent devices. As for the semiconductor photodetectors, one of the most prominent advantages is its capability of been compacted into integrated circuits. Furthermore, photodetection arrays could thus been achieved. Basic structures of the semiconductor photodetectors could be categorized into PN diodes, Schottky diodes as well as field effect transistors *etc.*.

128 In this work, we review the structures and devices based on ferroelectrics and 2D materials hvbrid system for photodetection. Fundamentals of the 2D materials and ferroelectrics 129 130 including structure, electrical, optoelectronic and interaction of the hybrid system are 131 presented. After that, various structures and corresponding nano devices for photodetection are discussed in detail, including PN junctions, field effect transistors and other types of 132 133 devices. Performances of the hybrid devices was summarized and discussed. This review 134 outlines the important aspects of the ferroelectrics-2D materials hybrid photodetectors and is 135 certainly of great interest for design novel photodetectors.

136 2. Fundamentals of 2D materials and ferroelectrics

137 **2.1. Fundamentals of 2D materials**

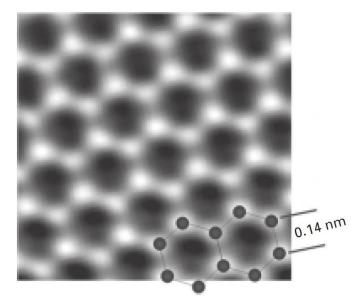
Exfoliation of the monolayer graphene has opened the door to research 2D materials. Monolayer graphene was applied in the FET and the outstanding electrical and structure property were observed. With deep exploration of graphene and its relative derives, as well as other 2D materials with similar structure for instance the hexagonal-boron nitride (h-BN), TMDs and black phosphorus (BP). These novel 2D materials share excellent optical and optoelectronic properties, which attracting more research for optoelectronic devices.

144 2.1.1. Graphene

145 It was convinced that nano-materials were hardly remain stable due to thermal fluctuation, 146 which consequently lead to decomposition of the materials. In this case, the thermally stable 147 and chemically inert graphene has brought big surprise to scientist, leading to booming 148 development of 2D materials research area in the past decades.[33, 59, 60] Researchers tried 149 to add the "fresh blood" into the "old fashioned" methods, devices and systems to create 150 novel structures and to improve the performance.

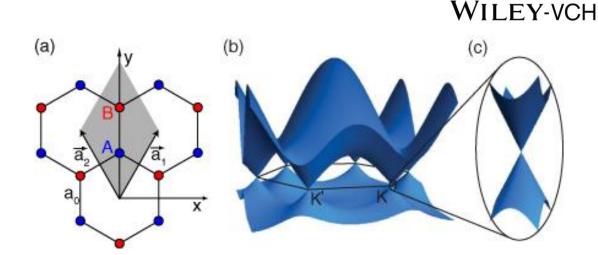
151 Graphene has in-plane chemistry bond connecting the atoms and can stack with Van der 152 Waals forces between layers. The structure of graphene is hexagonal arrangement of sp^2 -153 bonded carbon atoms with zero bandgap and Dirac point. In graphene, single layer of carbon 154 atoms with sp^2 -hybridization arranged in a honeycomb lattice, which is just one atom thick at 155 vertical dimension (about 0.14 nm). Each carbon atom in-plane bonds to other three nearest 156 atoms with a distance of 1.42 Å, shown in Figure 3.[61] The lattice of graphene can be 157 considered as two interpenetrating triangular sub-lattice A and B, see in Figure 4(a). Band 158 structure in graphene materials could be modeled by the tight-binding approximation as well 159 as calculated based on the first principle. [62, 63, 64], as shown in Figure 4(b) and (c).

160 The p_z orbitals remained, which do not involve in the covalent bonding, is responsible for the 161 electric conductivity. Graphene is a promising candidate for electronic devices with 162 outstanding electrical properties. Conductivity and mobility of the graphene nanosheets



163

164 Figure 3. Atomic structure of graphene nanosheets demonstrated the bond between the atoms 165 and the honeycomb structure of the graphene layer (courtesy of Berkeley's TEAM05, 2009). 166 mostly depend on the defect scattering process, which is almost independent from temperature. 167 [65] The minimum conductivity of graphene theoretically exhibits at the Dirac point as $4e^2/\pi h$. The electron mobility ranges from ~0.67×10⁴ cm²V⁻¹s⁻¹ up to 10⁶ cm²V⁻¹s⁻¹ in the 168 169 form of suspended nanosheets or supported by SiO₂/Si substrates. [30, 66, 67] Meanwhile, high current carrying capacity of ~5.8×10⁶ A·cm⁻² and ~1.8×10⁹ A·cm⁻² in graphene/Cu nano-170 171 composite wires and on synthetic diamond substrate, respectively.[68, 69, 70] Such high 172 current carrying capacity is particularly feasible for the energy storage system and device 173 minimization. Additionally, high thermal conductivity ranging from ~4840 W/m·K to 5300 174 $W/m \cdot K$ has been observed in layered graphene nanosheets, indicating their outstanding heat 175 dissipation capability, which can be beneficial for batteries and thermal conductive devices. 176 [71]Relative low contact resistance 100 Ω ·µm between graphene and metal electrodes allows 177 the application of electronic devices with low Schottky barrier height.[72] Graphene is 178 different from conventional metals not only due to its 2D structure and transparency in a wide 179 band incident light but also because of its ambipolar field effect transport property. Graphene 180 is consequently known as the "semimetal".[73, 74, 75, 76, 77, 78]



181

182 Figure 4. (a) lattice, (b) band structure and (c) zero-bandgap achieved by tight-binding
183 approximation

184 As the zero-band gap structure, graphene should theoretically be capable of responding to all 185 the photons, which consequently leads to the advantage of wide band detection from 186 ultraviolet to infra-red and all the way to Terahertz region.[31, 79, 80] In addition to the wide 187 band response properties, pristine monolayer graphene is of high transparency, with 188 absorption of 2.3% in a wide band. [81] Such high transmittance brings the opportunity for 189 graphene being applied as transparent electrodes, especially for those allow large absorption 190 area. Moreover, broad band absorption of graphene could be modulated by shifting the 191 electronic Fermi level, which could consequently dominate the photon transition in graphene 192 nanosheets.[82, 83] With interaction of incident light, energy could be converted among 193 carriers, photons and phonons in graphene by transition of the charge carriers (electrons and 194 holes). Macroscopic phenomena such as photon absorption, [84, 85] nonlinear optical 195 properties[86, 87, 88], plasmons,[89, 90] and photo-current have been observed.

196 2.1.2. Transition Metal Dichalcogenides

197 Another group of 2D materials with intrinsic bandgap and similar electrical properties, as well

as optoelectrical properties with graphene are TMDs. TMDs with chemical formula MX₂, is a

199 group of materials composed of transition metal (eg. Mo, W, etc.) and chalcogen (eg. S, Se,

200 Te, etc.), as shown in Figure 5. TMDs share similar structures that can be categorized into

IVB	VB	VIB	VIIB		VIII		VIA
Ti	²³ V	²⁴ Cr	²⁵ Mn	²⁶ Fe	²⁷ Co	²⁸ Ni	¹⁶ S
⁴⁰ Zr	⁴¹ Nb	42 Mo	Тс	Ru	⁴⁵ Rh	⁴⁶ Pd	³⁴ Se
⁷² Hf	⁷³ Ta	⁷⁴ W	⁷⁵ Re	⁷⁶ Os	⁷⁷ Ir	⁷⁸ Pt	⁵² Te

201

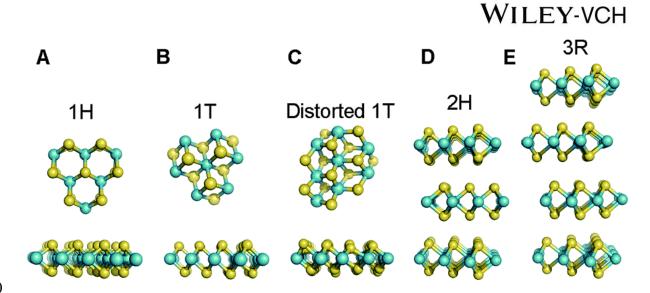
Figure 5. Elements for TMDs. The ones marked in orange means only some of thecompounds can form int layered structures

204 several polytypes varying in stacking orders and metal atom coordination, as shown in Figure 205 6.[91] The 2H, 3R and 1T phases are the most stable and common structure of TMDs, among 206 which 1H is the most stable and the most studied structure. 3R and 1T phase are metastable 207 and can be converted into 2H by annealing, heating or laser excitation. [92, 93] Properties of 208 different compounds varies at conductivity. For example, compounds with M=Mo and W, 209 X=Se and S are semiconducting,[94, 95, 96] while with M=Nb and Ta are metallic.[97] 210 TMDs experience the transition of indirect bandgap to direct optical bandgap with the number 211 of layers decreased to bilayer or monolayer, as shown in Figure 7.[98] The bandgap ranges 212 from 1.0 eV to 2.1 eV, see in Table 1. Some of the TMDs, like TiS_2 and WT_2 , show zero 213 bandgap structure, being similar to graphene. Bandgap modulation is desired for applications 214 of TMDs in nano-devices under certain circumstances due to the requirement of tunable 215 electronic properties. Therefore, bandgap modulation by strain engineering, electric field 216 control, alloying and hybrid system fabrication has been studied.

217 MoS₂ is considered as a typical representative TMD and has been recently intensively studied.

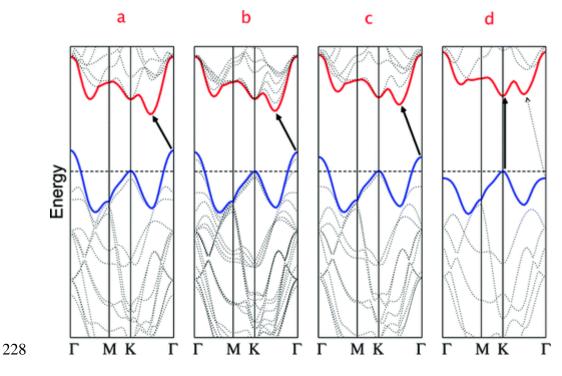
218 MoS_2 has transition bandgap of 1.2 eV~1.9 eV with the thickness decreased from bulk or few-

219 layer to monolayer. The optical properties of MoS₂ depends on its bandgap structures. With

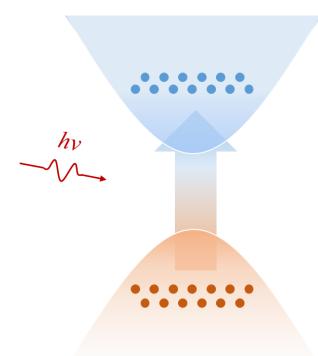


221 **Figure 6.** structures of the TMDs.

bandgap ranges from 1.2 eV to 1.9 eV, corresponding to wavelengths ranging from 652.6 nm to 1033.3 nm. Linear absorption in the valence band occurs with incident light whose photon energy is higher than 1.2 eV. Photocurrent is generated from the electrons in the conductive band, as shown in Figure 8. Such optoelectronic property and the electrical conductance, as well as carrier mobility of MoS_2 nanosheets show great potential in photodetection with wide band response and high sensitivity.



229 **Figure 7.** Electrical properties of the layered MoS₂



230

231 Figure 8. Non-equilibrim carrier generated by incident light

232 2.1.3. Other novel 2D materials

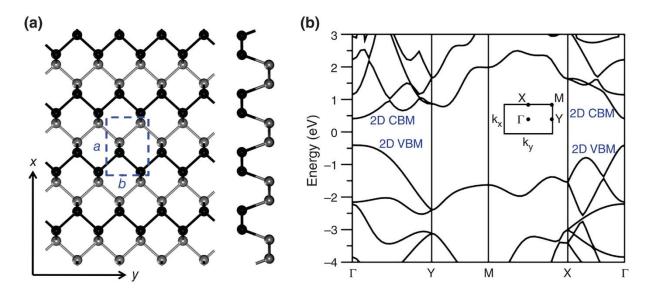
Recently 2D materials composed of group-IV (Si, Ge and Sn) elements have also emerged. Silicene and germanene has similar structure as graphene with honeycomb lattice arranged inplane and Van der Waals bond between adjacent layers. They have application potential in the integrated circuits due to their Si-technology compatibility. Another group IV atomic material that has been intensively studied is stanine whose structure also resembles graphene with two common allotropes: α-tin with face-centered cubic lattice like diamond and β-tin with facecentered tetragonal lattice.

Another category of novel 2D materials, the black phosphorus (BP), was first synthesized a century ago and recently attracts lots of interest due to its direct bandgap in bulk and monolayer ranges from 0.33 eV to >1 eV. BP could thus be applied in the mid-infrared photodetectors. Scotch tape method could achieve exfoliated monolayer BP and thickness of monolayer BP could be 0.7-0.85 nm. Structure of the BP is shown in Figure 9. As for the electric properties of BP, the electron and hole mobilityS were measured to be >1000 cm²V⁻ 1s⁻¹ at room temperature with high on/off ratio in the application and on/off ratio, together

with its band structure, making it suitable for photodetection.[100, 101]

248 **2.2. Fundamentals of ferroelectrics**

Ferroelectrics are a group of materials with asymmetry lattice structure, resulting in dipoles in the lattice and capable of being modulated by the external stimuli. One of the most typical characteristics of ferroelectrics is the spontaneous polarization, i.e. the positive and negative charge centers in the original cell of the lattice do not coincide without external electric field



253

Figure 9. (a) Lattice structure and (b) electrical band structure of phosphorene.

Table 1. Bandgap of typical MX₂ (M=Mo, W; X=S, Se, Te)

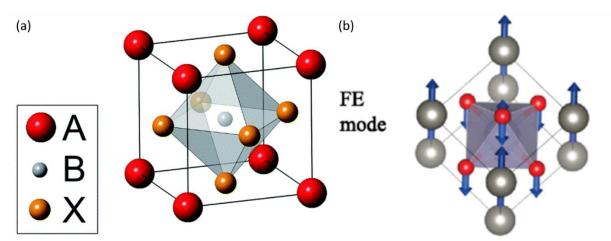
TMDs	Number of layers	Band gap [eV]	Reference
MoS ₂	monolayer	1.9-1.95	[150, 151]
MoS_2	bulk	1.20-1.29	[98, 152, 153]
MoSe ₂	monolayer	1.44-1.55	[154, 155]
MoSe ₂	bulk	1.1	[154]
WS_2	monolayer	1.80-2.05	[155, 156, 157]
WS_2	bulk	1.30-1.35	[153, 158]
WSe ₂	monolayer	1.65-1.70	[159, 160]
WSe ₂	bulk	1.2	[161]
MoTe ₂	monolayer	0.90-1.10	[162, 163, 164, 165]
MoTe ₂	bulk	0.88	[164, 165]
WTe ₂	monolayer	0.18	[166, 167]
WTe ₂	bulk	0.7-0.81	[166, 168]

256 within a certain temperature range. Other properties including the dielectricity, 257 piezoelectricity, pyroelectricity and related effects (for instance electro-optical effect, 258 acoustic-optical effect, photorefractive effect as well as nonlinear optical properties) make 259 them particularly suitable for varieties of applications. These phenomena related to the lattice 260 structure of ferroelectrics could be further investigated by "ferroelectric domain" structure in 261 the materials. Domains are defined as small region of lattice with the same polarization 262 direction, which is correlated to the lattice asymmetry, piezoelectricity and ferroelectricity of 263 the materials. According to the lattice structure, ferroelectrics are categorized into perovskite, pyrochlores, the tungsten-bronze group and the bismuth layer structure group. In combination 264 265 with 2D materials, the ferroelectrics could be applied as the functional layer due to the alter of polarization with external electric field switching. Typical ferroelectrics including inorganic 266 267 perovskites with ABO₃ structure, like Pb(Zr,Ti)O₃ (PZT), PbTiO₃ (PT), Pb(Mg,Nb)O₃-PbTiO₃ 268 (PMN-PT), BaTiO₃ (BTO), (Bi,Na)TiO₃-BaTiO₃ (BNT-BT), (K, Na)NbO₃ (KNN) and 269 organic polymers like Poly(vinylidene fluoride) (PVDF) and Methylammonium Lead Iodide 270 (MAPbI₃).

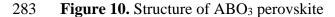
271 2.2.1. ABO₃

272 Among all the ferroelectrics, the inorganic ferroelectrics with genetic composition of ABO₃ 273 are the most studied and most widely applied. Library of ABO₃ perovskite contains 274 compounds like PZT, PT and BTO, as shown in Figure 10(a).[102, 103, 104] These ABO₃ 275 ferroelectrics could be further divided into lead-containing and lead-free compounds. PZT is 276 the dominating ferroelectric materials in the high-end commercial market for its remarkable 277 ferroelectricity and mature ceramic fabrication process. Despite the high performance of 278 devices with lead-containing materials, another group of lead-free oxides like BTO, BNT and 279 BFO are attracting increasing attentions due to their environment-friendly feature and good 280 ferroelectric properties.

A-site driven ferroelectric distortions is shown in Figure 10(b).[105] The ferroelectric domain



282



284 strongly impacts the ferroelectricity. Ferroelectric domain refers to a region where the polarization shares the same orientation without any external stimuli. That is to say, all the 285 286 domain states have the same energy. Furthermore, if an external electric field was applied to 287 the ferroelectric material, polarization tends to be aligned to the same orientation and the free 288 energy would be weakened. Consequently, the permanent polarization could be achieved by 289 applying a large enough external electric field. The most important characteristic of the 290 ferroelectrics is the hysteresis loop, known as the fingerprint of the ferroelectricity, which 291 reveals the non-linear relation between the polarization and external electric field. In addition, 292 the direction of polarization could be reversed by switching the electric field. Different 293 crystallographic forms (e.g. texture, polycrystalline and epitaxial) may significantly influence 294 the material properties and their applications. For instance, the grain and grain boundaries 295 have modulation effects on the polarization and other parameters.[106] Defects in the nano 296 layer structure could lead to stress inside the material and, as well, impact the device 297 performances.[107]

Other common methods to characterize the ferroelectricity of materials include the capacitance-voltage (C-V) characteristics, also known as the "butterfly curve", leakage current and fatigue measurements. Key parameters of ferroelectric materials include the

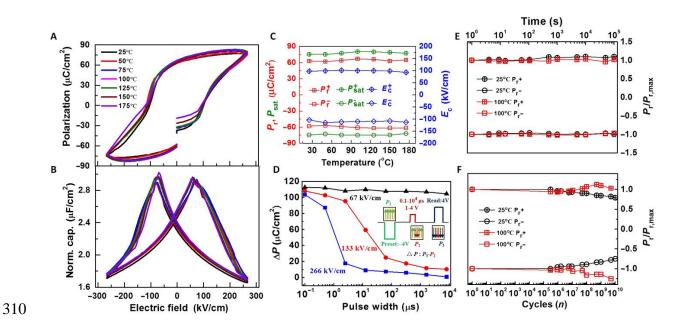
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dielectric constant, coercive field, remnant polarization etc. Figure 11 is the measurements of
PZT layer. [108]

Most of the ferroelectrics have intrinsic large bandgap (see <u>Table 2</u>). Ferroelectric thin films possess optical properties including high transparency at visible band, high dielectric constant nonlinear optical response which are particularly useful in lasers for nonlinear optical frequency conversion. In ferroelectric materials, polarization depends on the electric field and incident light, which could be expressed as

308
$$\vec{P} = \varepsilon_0 \chi^{(1)} \cdot \vec{E} + \varepsilon_0 \chi^{(2)} : \vec{E}\vec{E} + \varepsilon_0 \chi^{(3)} : \vec{E}\vec{E}\vec{E} + \dots = P^{(1)} + P^{NL}$$

309 where the first term is the linear optical property of with $\chi^{(1)}$. The $\chi^{(2)}$ and $\chi^{(3)}$, are the



311 Figure 11. Electrical properties of PZT thin film. (a)P-E and (b)C-E hysteresis loops at 312 various temperatures. (c) Remnant, saturation polarizations, and coercive field as functions of 313 temperature. (d) PUND switching polarization as a function of pulse width at different 314 voltages. The inset shows the measurement sequence. Retention (e) and fatigue (f) 315 measurements at two typical temperatures second- and third-order nonlinear optical 316 susceptibilities, which correspond to nonlinear optical properties of the material. The second 317 order nonlinearity could induce the sum- and difference-frequency generation, Raman scattering, Brillouin scattering and optical parametric oscillation (OPO) etc. For the third 318

Ferroelectrics	Band gap (eV)	Reference		
	2440	[169, 170,		
PZT (Pure)	3.4-4.0	171]		
PZT (Doped)	2.74-3.10	[169]		
ВТО	2.6	[172]		
R' BFO	2.65-2.82	[173, 174]		
T' BFO	3.1	[173]		
HZO	bulk	[175][175]		

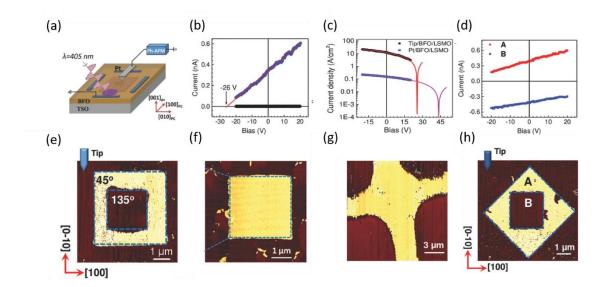
319 **Table 2.** Bandgap of the typical ferroelectrics

320 order nonlinearity of the material, phase conjugation, four-wave mixing and nonlinear321 absorption could be observed.

322 Polarization of the domains could be modulated by the external optical field. [2, 109] Incident 323 light interacts with ferroelectrics generally in two ways. One is the thermal induced 324 polarization reverse. The incident light with high energy intensity illuminating on the 325 ferroelectrics, which results in continuous increase of temperature in local ferroelectrics and 326 eventually induces polarization switches.[110, 111] It is noticed that such thermal induced 327 polarization switch is irreversible. The other method for light induced polarization switch is 328 based on the open circuit voltage generated from the ferroelectrics, which is also known as 329 bulk photovoltaic (BPV) effect.[112] Li et al. has reported the polarization switch by BPV 330 effect in BiFeO₃.[113] With light on the surface of ferroelectrics, equilibrium carriers were 331 generated and thus induce photo current Iph in the layer. A build-in electric field was 332 established along the direction of photo current which is, equivalently, considered as a current 333 source. If the build-in electric field could be raise to values higher than the coercive field, 334 polarization of the ferroelectrics can be switched. It is worth mentioning that the polarization 335 is reversible with incident light illuminating on different regions. Moreover, controlling of the 336 strong laser field, tip-enhancement of the light as well as tuning illumination area could also 337 achieve reversible ferroelectric polarization switching, as shown in Figure 12. [114]

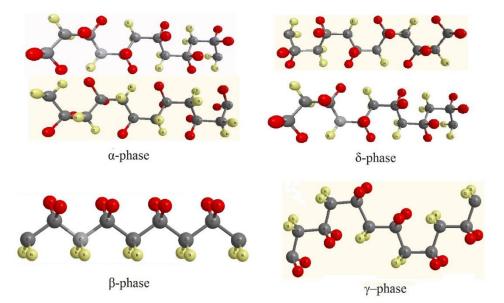
338 2.2.2. Ferroelectric Polymers

339 Moreover, organic ferroelectric polymers have also been studied due to their good mechanical 340 property and flexibility. The organic ferroelectric materials are represented by PVDF and its 341 derives. PVDF is one of the most studied material. There are four typical lattice structure in PVDF including α , β , γ and δ phase, which is also known as the I, II, III and IV phases. 342 343 Structure of PVDF-TrFE was shown in Figure 13. The α-PVDF forms into orthorhombic cell 344 with two chains packing in opposite directions resulting in canceling of the dipole moments, 345 which consequently makes the α -phase PVDF non-polar and paraelectric. β -PVDF shares o-346 phase as well yet the structure of the lattice is in all-trans planar zigzag conformation with 347 fluorine atoms on one side. β -PVDF could thus achieve the highest dipole moment and



348

Figure 12. Various methods for the light induced polarization in ferroelectric BFO layer. (a) 349 350 Schematic illustration of the device and the light incidence. (e) is polarization switching 351 generated from the polarized incident light. (b) is Local current-voltage characteristics with and without illumination at tip-enhancement method and (f) is the corresponding PFM result. 352 353 (c) is the current density-voltage dependence of tip/BFO/SRO and the Pt/BFO/SRO capacitors 354 and (g) is the PFM amplitude which demonstrated polarization switching with illumination as 355 a result of photocurrent density. (d) and (h) are the polarization switching via tuning 356 illumination.



358

359 **Figure 13.** Structure of PVDF crystalline.

become the most popular structure of PVDF with the best ferroelectricity and piezoelectricity among all the phases. Crystalline PVDF with γ -phase is monoclinic with partial dipole moment, which also show ferroelectricity. The δ -phase structure resembles the α -phase but with the second chain rotating 180° along the chain axis. Such structure could result in the polar behavior and show ferroelectric property. P(VDF-TrFE) polymer is composed of PVDF and TrFE, which is of the most popular ferroelectric polymers among the PVDF based materials.

Incident photons with high energy like X-ray could generate defects in P(VDF-TrFE) and free carriers generated have impact on the reversal of polarization. It was reported that with X-ray illuminating on the polarized P(VDF-TrFE) films, a clear phase difference of 180° as well as domain boundaries was observed. The loss in ferroelectricity will significantly reduce the poled domain area with X-ray irradiation and the domains would be rarely poled after illumination for 60 minutes. [115]

373 **2.3. 2D materials/Ferroelectrics hybrid system**

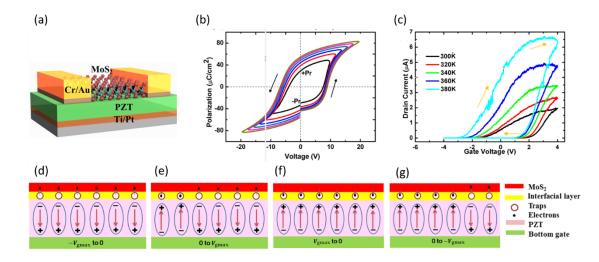
374 Compared to 2D materials on SiO_2/Si substrates, suspended counterparts MoS_2 has enhanced 375 conductivity. However, if one changes the supporting substrates from SiO_2/Si to other

functional ones, the properties of 2D materials and thus related device performances could be effectively modulated. In addition to holding the 2D materials, these functional substrates play an important part in mechanical, chemical, electronic and optoelectronic properties of the 2D nanosheets. Defects and impurity at the interface as well as the lattice mismatch between the MoS_2 and substrate could all impact the structure of the nanosheets. Then the related charge transfer, interface strain, dielectric screening effect, as well as the optical interference in the 2D semiconductor subsequently impact the device performances.

383 2.3.1. Electrical interaction of 2D/ferroelectrics hybrid system

Polarization switching in ferroelectrics has been proved to be able to establish a build-in
electric field in 2D materials, which could further modulate the electrical properties of the 2D
materials.

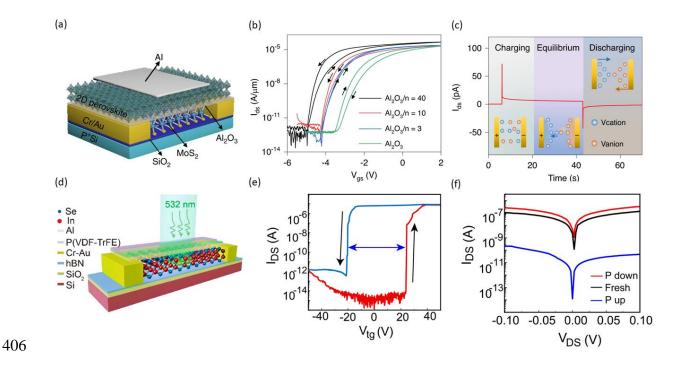
Therefore, FETs combining 2D materials and ferroelectric layers has been investigated. One of the most typical phenomena observed in the early studies was that the clock-wise hysteresis loop in the transfer property of FET devices, as shown in <u>Figure 14</u>.[116] This hysteresis loop was believed to be originated from adsorbents of water molecules rather than ferroelectric



391

Figure 14. Hysteresis behaviors induced by the interfacial states of MoS₂/PZT FETs. (a) is the devices structure. (b) is the polarization-voltage characterization of PZT film and (c) is the transfer characteristics of the device with anti-hysteresis loop. (d)-(g) is the physical mechanism of charge trapping and de-trapping at the interface of MoS₂/PZT hybrid system.

396 polarization switching which should induce anti-clockwise loop [153,154]. Such clockwise 397 hysteresis was also observed in other 2D materials/ ferroelectrics hybrid system. In addition to 398 water molecules absorbents, other possible reasons like oxide charge trapping and surface 399 charge trapping are also discussed. [117, 118] Hysteresis in ferroelectric devices have 400 undermined the reliability of the devices and scientists have dedicated to solve this issue. Jang 401 et al. has proposed a probable method to eliminate the hysteresis generated from charge 402 trapping in the ferroelectrics. [119] In the devices contain ferroelectric layer, two hysteresis 403 loops with opposite direction exist which is the loop induced by ionic migration in 2D 404 ferroelectrics and loop induced by charge trapping, respectively. These two negative effects 405 might neutralize with each other by modulating the activation energy for ionic migration in

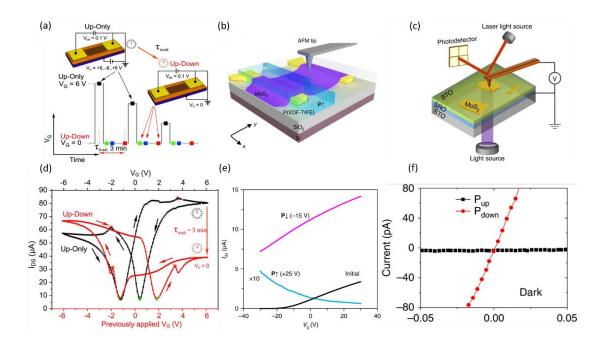


407 **Figure 15.** (a) MoS_2 phototransistor with $Al_2O_3/2D$ perovskite heterostructure dielectric. (b) 408 Transfer characteristics of the devices. The neglectable hysteresis loop is achieved. (c) is the 409 schematic illustration of charging-discharging process. (d) is the device structure of InSe 410 photodetectors gated by P(VDF-TrFE). (e) is the anti-clockwise memory window achieved 411 with bias voltage switching from -40 V to 40 V and (f) is the output characteristics of the InSe 412 FET with different polarization states.

ferroelectrics, see in Figure 15(a). These rectified devices have proved excellent rectifying characteristics and high performance in photodetection. [120] InSe photodetectors gated by ferroelectrics (shown in Figure 15(b)) has reported anti-clockwise hysteresis in the experiments, as shown in Figure 15(c).

417 Despite the charge trapping induced clockwise hysteresis, the hysteresis generated 418 ferroelectrics could also be observed in the devices as shown in Figure 15 (d). Anti-clockwise 419 memory window was observed with bias applied from -40 V to 40 V, shown in Figure 15 (e) 420 and the electrical properties varied with different polarization states, see Figure 15 (f).

In addition to the hysteresis observed in 2D materials and ferroelectrics hybrid system. The dielectric screening effect is capable of modulating the electron-electron interactions as well in the layer adjacent to the substrate, leading to band structures variation and Fermi level shift. Moreover, the electronic transport of 2D materials could be tuned by ferroelectrics with



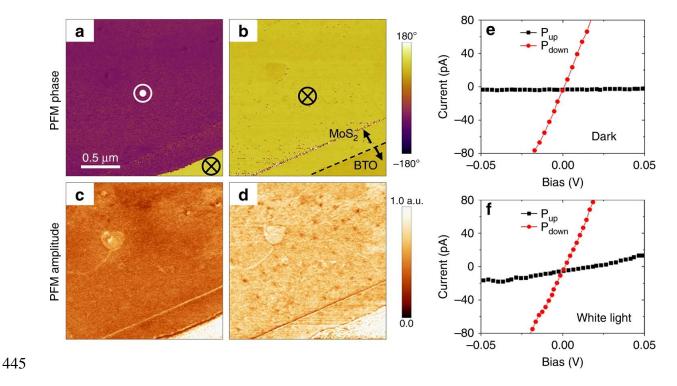


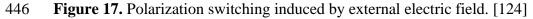
426 **Figure 16.** Electrical properties of the devices modulate by ferroelectric polarization. (a) and 427 (d) are demonstrated the hysteresis reversal in graphene-PZT FeFETs and the I_{ds} - V_{gs} voltage 428 of +25V and down poling voltage of -15V.[122] (c) and (f) demonstrated the polarization 429 induced dark current variation in the MoS₂/BTO FETs.[113]

polarized-up and -down were measured.[121] (b) and (e) is the is the I_{ds} - V_{gs} characteristics of 430 431 MoS2 FETs with PVDF as ferroelectrics and polarized by up poling polarization, as shown in 432 Figure 16.[121, 122, 113] For example, the carrier type of the 2D materials could be 433 modulated by the ferroelectric polarization switching. [123] Reversal of the polarization of the 434 underneath ferroelectric film has led to the conversion of graphene from p-type to n-type, 435 resulting in the reversible switching of the resistance in graphene. Similar results has been 436 achieved by other researches with different 2D materials like MoS₂, MoTe₂ and InSe.[122, 45, 437 120] Low-voltage operation could be achieved with high-k ferroelectrics and the retention 438 time of the devices could be improved [159].

439 2.3.2. Optoelectronic properties in 2D/ferroelectrics hybrid system

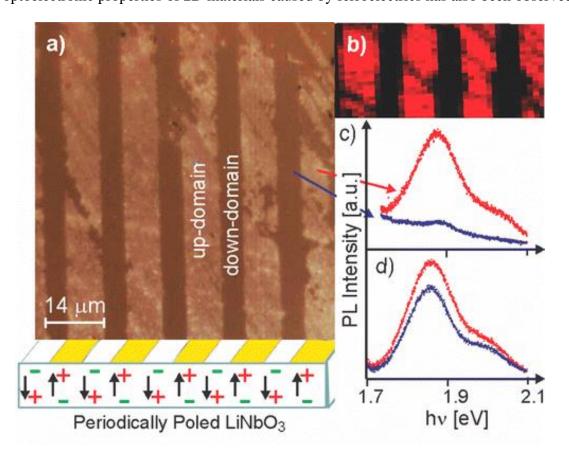
With 2D semiconductor in combination with ferroelectric layers, memory devices are capable of being written and erased both electrically and optically.[14] Moreover, ferroelectric films would be much easier to achieve polarization reversal than the pristine ferroelectrics with the assistance of 2D materials due to the compensation charge generated from 2D materials with incident light. As shown in Figure 17, MoS₂/BTO/SRO structure was fabricated and the





447 underneath BTO was able to be polarized by external electric field with MoS₂ on top. Ultra-448 violet (UV) light irradiation was then applied in the structure and optical induced polarization 449 reversal was observed, as shown in Figure 17(b)-(e). The illumination of the structure leads to 450 an accumulation of photon-generated carrier at the interface. Charge accumulation could 451 modulate the built electric field and consequently change the electric field applied on the BTO, 452 resulting in polarization switching in the BTO layer.[124] Polarization could also be 453 modulated by the intensity of incident light and the piezo-response microscopy (PFM) 454 amplitude signal, which varied because the photon-induced carriers devoted to the modulation 455 of the electric field at the interface. Similar X-ray induced polarization has been studied with 456 different ferroelectrics. [115]

In addition to photon induced polarization reversal with assistance of 2D materials, the impacton optoelectronic properties of 2D materials caused by ferroelectrics has also been observed.



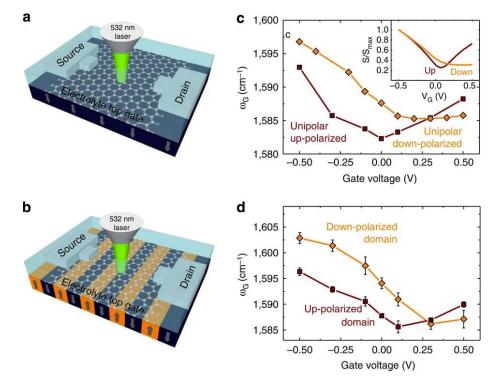
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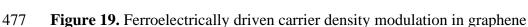
460 Figure 18. Optical microscopy of selective deposited MoS2 on pre-polarized LN and the

461 photoluminescence of the MoS₂ island. [125]

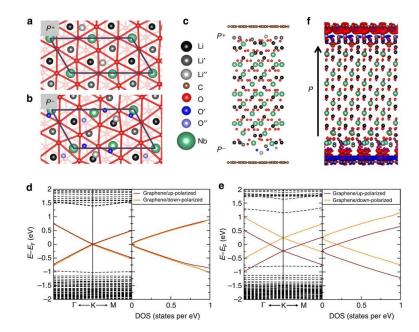
LiNbO₃ (LN) is a ferroelectric material widely applied in optical devices thanks to its 462 463 outstanding nonlinear optical properties. LN could be pre-polarized and applied as substrates 464 for 2D materials. [125] MoS₂ was deposited on the periodically poled LN substrate. Selective 465 growth of the MoS₂ was observed where enhance deposition of MoS₂ was found on the polarization "up" domain compared to polarization "down" domain. Optical properties of the 466 467 deposited MoS₂ are influenced by the polarized LN, as illustrated in Figure 18. Polarization of 468 the LN substrate could not only influence the growth but also the carrier transport of the MoS₂ 469 overlayer.

470 Chemical vapor deposition (CVD) fabrication of MoS_2 requires high temperature of over 471 600°C, which is higher than the Curie temperature of many ferroelectrics and leads to the loss 472 of polarization. Therefore, an alternative method, namely mechanical transfer for the 473 realization of MoS_2 on ferroelectrics has been developed. [126] For instance, CVD grown 474 WS₂ monolayer was mechanically transferred to a pre-polarized ferroelectric substrate and 475 photoluminescence (PL) characterization of the WS₂ was measured. The spatial variation of





476



479

480 Figure 20. Theoretical study of the ferroelectrically control of carrier density in graphene481 with first-principle DFT.

482 PL spectra indicates the effective modulation of WS₂ monolayer by ferroelectric polarization.
483 [126]

484 Photo-induced polarization in 2D/ferroelectrics hybrid structure has been proved to be 485 dependent on the intensity of incident light. The ferroelectrics could also drive spatial carrier 486 density modulation in the 2D materials of the hybrid structure, [127] as shown in Figure 19 487 reported by Baeumer et al. Characteristic peaks of Raman spectra shift in different 488 polarization domain of the LN crystal. Two orders of magnitude carrier density difference 489 were observed, which could origin from the graphene/LN interfacial chemistry effects. The 490 interaction has also been theoretically calculated by the first-principle density-functional 491 theory (DFT) calculations, as shown in Figure 20. Structure of the interface was constructed 492 and the polarization was applied, as shown Figure 20(f). Calculation of the carrier density in 493 graphene revealed that symmetrical charge densities in graphene was 6.75×10^{12} .

494 **3.** Photodetectors based on 2D materials and 2D materials/ferroelectrics hybrid system

495 **3.1. Fundamentals of photodetection**

496 2D materials with their superior photonic and optoelectronic properties has been extensively 497 studied in nano devices. The TMDs nanosheets are a typical group material among the large 498 amount and types of the 2D materials. The TMDs could be primarily considered as 499 semiconductors with direct or indirect bandgap. Therefore, the principle and understanding of 500 conventional semiconductor photodetection could be transferred to TMDs photodetection. 501 The incident light generates carriers in semiconductors and they are then transported to 502 electrodes. It is noticed that the signal amplification is sometimes applied in this procedure 503 particularly in photodetectors due to the requirement of weak signal detection. Photodetection 504 mechanism mainly consist of the photoconductive effect and photovoltaic effect. There are 505 three main device structures for semiconductor photodetectors, the PN junction and related 506 devices, Schottky junctions and field effect transistors.

507 Semiconductors could absorb the illuminated light and transfer photons to signals like voltage 508 or current. This photodetection process could occur only when the incident photons possess 509 larger energy than the bandgap of semiconductor materials, i.e.

$$510 \qquad \hbar v \ge \hbar v_0 = E_g \ (1)$$

where the $\hbar v_0$ is the threshold energy that enables the intrinsic absorption. Moreover, for semiconductors with the indirect bandgap, the probability of the transition is much smaller than that of direct transitions, due to the participation of the phonons. Other absorption including exciton absorption, free carrier absorption and impurity absorption. During the photodetection, electrons in the valence band transit to the conductive band under illumination and generate extra electrons and holes, leading to signals of current or voltage. Photogenerated current could be expressed as

518
$$I_c = q\eta \frac{P}{hv}$$
 (2)

519 Consider $A = \frac{q\eta}{hv}$ is the proportionality constant, which represents the sensitivity of the 520 photodetector.

521 Mechanism of photodetection mainly includes the photoconductive and the photovoltaic ones. 522 The conductivity increases of semiconductors due to light illumination has been briefly 523 introduced before (see section 2.3), which is known as the photoconductive effect, as shown 524 in Figure 21.

- 525 The generation rate of the photogenerated carriers is proportional to incident light intensity. 526 The photogenerated carriers constantly generate and recombination, the density of photon-527 generated carriers is
- 528 $\Delta n_0 = \Delta p_0 = g\tau \quad (3)$
- where g is the generation rate of photogenerated carriers, τ is the average carrier life-time.
 Consider the incident light power of P, g could be written as

532

531

533 **Figure 21.** Basic principle of photoconductive current generation

534 where η is the quantum efficiency, A and L is the cross-section area and the length of the 535 material, respectively. Short-circuit photocurrent density with external electric field is

536
$$\Delta J_0 = E \cdot \Delta \sigma = q \tau \eta \left(\mu_n + \mu_p \right) \frac{P}{h v A L} E$$
(5)

537 Electrical conductivity and photocurrent both increase as the intensity of illumination538 augments. Photocurrent is then:

539
$$I_{p} = \frac{U\Delta\sigma A}{L} = \frac{qUA(\Delta n\mu_{n} + \Delta p\mu_{p})}{L} = \frac{qNU}{L^{2}}(\Delta n\mu_{n} + \Delta p\mu_{p})$$
(6)

540 where N is the number of generated electron-hole pairs; τ_n and τ_p are corresponding life-541 time of electrons and holes generated, respectively.

542 With illumination on the inhomogeneous semiconductor, the build-in electric field is formed 543 and photo-generated current is observed when the circuit is shorted. Such optoelectronic 544 effect is photo-voltaic effect.

Based on photoconductive and photovoltaic mechanism, different devices are developed, in 545 546 which photoconductors and photodiodes are two typical representatives. Photoconductors are 547 based on photoconductivity. Photo-conductors usually has wide band response, relatively high 548 operating current and high sensitivity. With the incident light, the non-equilibrium carriers 549 increase and consequently improve the conductivity of the materials, and the resistance is thus 550 reduced under illumination.[128, 129] The photoconductive effect is sensitive to the 551 nanostructure as well as the doping and defects of the semiconductors. Photoresistors based 552 on 2D materials with wide band responsivity has been widely studied and reported by 553 researchers. [130] It was demonstrated that the 2D materials are able to cover the UV to infra-554 red band with high responsivity and ultrasensitive properties.

555 Photodiodes are based on the photo-voltaic effect, which is also known as barrier-type 556 photodetectors. Photodiodes include PN junction, the PIN junction, heterostructure and 557 Schottky diodes.

29

558 Compared to photoconductors which require external voltage, photodiodes have certain 559 polarities and thus the signals could be transferred without external voltage. Photodiodes also 560 show fast responsivity and good frequency response.

561 Taking PN junction as an example to explain the photodetection process, the barrier region in a PN junction shares relatively strong build in electric field (from n-region point to p-region). 562 563 Photo-generated carriers move in opposite directions under the build-in electric field. The 564 electrons in p-region move to the n-region while the holes enter the p-region. Such movement 565 of the electrons and holes consequently lead to potential reduction in the n-region and rise in 566 the p-region. Electromotive force (EMF) across the PN junction generated with illumination results into a pressure drop $qV_D - qV$ and forward current I_F . In addition to the photoresistor 567 568 and PN diode, another group of devices enable photodetection could are as well studied 569 profoundly, known as the phototransistors.

570 **3.2. Figures of merit in photodetection**

The most important parameters for photodetection are identified as speed, responsivity and sensitivity. Other parameters including quantum efficiency, noise and gain are important figures of merit as well. It is noted that here we only consider the semiconductor photodetector to understand the operation of the semiconductor photodetector and figures of merit for photodetection which are of vital importance to the materials parameters, device structure and performance. Definitions of the parameters of quantum efficiency, responsivity, sensitivity, response speed and photo gain are as follows:

578 "Quantum efficiency" could be divided into internal and external quantum efficiency, which 579 are the most important parameters for semiconductor optoelectronic photodetectors. The 580 internal quantum efficiency (IQE) is define as the number of electron-hole pairs generated by 581 absorbing one incident photon, which is

582 $IQE = 1 - e^{-\alpha(\lambda)W}$ (7)

where $\alpha(\lambda)$ is the absorption coefficient of corresponding wavelength λ , W is the thickness 583 584 of the absorption layer. It is demonstrated that the IQE increases with the absorption 585 coefficient or the thickness of the absorption layer grows. In practical applications, there is no 586 way for photons reach the absorption layer through the surface of the materials. Photons go 587 through a heavily doped contact area with photon loss rather than passing through the surface 588 of materials to reach the absorption layer. Simultaneously, the reflection of the surface also 589 consumes part of the incident photons. Thus, the external quantum efficiency (EQE) is 590 defined as

$$EQE = (1 - R_f)e^{-\alpha(\lambda)d} \cdot IQE$$

$$= \frac{I_p/q}{P/hv}$$
(8)

592 where d is the thickness of contact area and R_f is the surface reflectivity on photodetector.

⁵⁹³ "Responsivity" of a photodetector is the voltage or current of photodetector output divided by ⁵⁹⁴ the input power, which could be categorized into spectral responsivity (R_{λ}) and integral ⁵⁹⁵ responsivity (R). If the photo-induced current (I_{ph}) is measured with incident power of P,

$$596 \qquad R = \frac{I_{ph}}{P} \ (9)$$

597 according to the definition of quantum efficiency, then

598
$$R = EQE \cdot \frac{q}{hv} \quad (10)$$

599 where q is the electronic charge.

"Sensitivity" of a photodetector is the minimum photon signal detected under certain
transmission bandwidth and rate. It measures the photoelectric conversion characteristics, as
well as the spectral and frequency conversion characteristics.

"Response speed" of photodiode is evaluated by the rise/fall time (τ_r/τ_f) of the detective 603 signal. The response speed is defined as the frequency where the photocurrent decreases to 604 $1/\sqrt{2}$ from peak in frequency domain. Incident photons will go into the semiconductor 605 606 through the surface layer, then photo-generated carriers and free electron-hole pairs shift 607 under the electric field. The time required for incident photons to be transferred to photocurrent is the "response time". Three main factors could affect the response time, 608 609 including the diffusion and transition time in the depletion region, as well as the RC time 610 constant of the photodiode.

The "noise equivalent power (NEP)" is another key parameter for photodetection, which refers to the input signal power which results in a signal-to-noise ratio (S/R) of 1 in a 1 Hz output bandwidth. [131]NEP has expressed the sensitivity of photodetectors. Another typical parameter being correlated to the NEP is the "detectivity" (D^*).

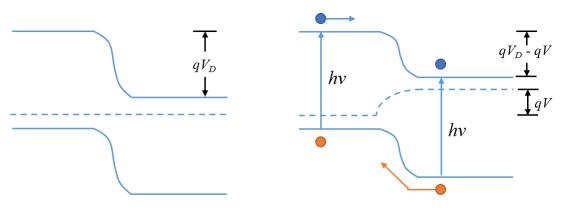
615
$$D^* = \frac{(A \cdot \Delta f)^{\frac{1}{2}}}{NEP}$$
 (11)

616 where, *A* is the area of the photosensitive region and the Δf is the frequency bandwidth of the 617 detector.

618 "Photogain" is a benchmarked parameter for photoconductive detectors, which is

619
$$G_{ph} = (I_{ph}/q)/(\Phi_{in}QE)$$
 (12)

620 where $\Phi_{in} = \frac{P}{hv}$ is the incoming photon flux. Here we bring another definition of External 621 Quantum Efficiency (EQE) for sensitized photoconductors as $QE = \eta_{trans}\eta_{abs}$, where η_{trans} is 622 the charge transfer efficiency and η_{abs} is the absorption efficiency, which demonstrates the 623 number of detected charge carriers per single incident photon. The photogain can also been 624 quantified by the ratio of the lifetime of the trapped carriers (τ_{life}) over the drift transit time 625 ($\tau_{transit}$). If we take a FET for example, a bias (V_{bias}) is applied to a FET device, the G_{ph} can



626

- 627 **Figure 22.** Band structure of PN junction and the mechanism of photodetection.
- 628 be defined as

629
$$G_{ph} = \frac{\tau_{life} \cdot \mu \cdot V_{bias}}{L^2}$$
(13)

630 where *L* is the channel length, μ is the carrier mobility.

631 **3.3. Photodetectors based on PN junctions**

632 For 2D materials, iron-doping and adsorbates of the materials are often applied to achieve p-633 type or n-type semiconductors, as shown in Figure 22. Structure of 2D materials applied in the 634 devices are basically categorized into the homojunction and heterojunction. Detectors based 635 on various 2D materials has been reported. [132] Graphene PN junction was formed by 636 applying voltages with opposite polarities on the top and bottom gate, as shown in Figure 23(a)-(c). Thermo-induced carriers were considered to play an important role in the 637 638 optoelectronic response of graphene, and the photocurrent was demonstrated to be >40 nA 639 with a relatively low voltage bias and an incident light with the wavelength of 850 nm. Responsivity was correspondingly measured to be 5 mA W⁻¹ which was relatively small 640 641 compared with FETs photodetectors, yet larger than the previously reported 1 mA W⁻¹. MoS2 homojunction photodetectors with a ultra-high responsivity of 7×10^4 A W⁻¹ and EOE>10% 642 has been reported by Huo et al. [133] p-type and n-type MoS₂ was achieved by chemical 643 644 doping and form a vertical junction as

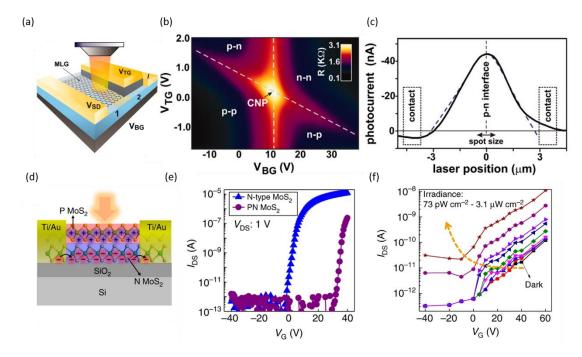
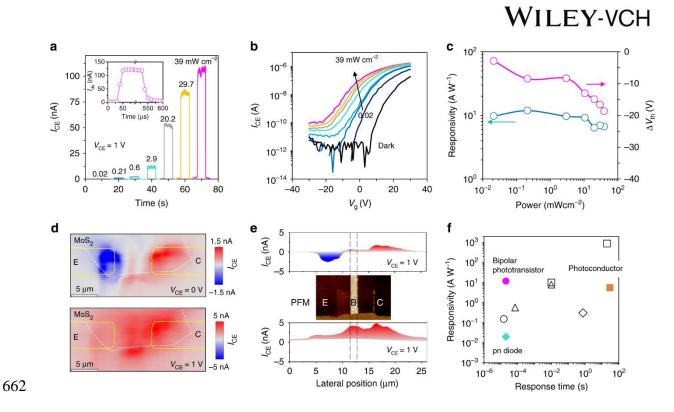


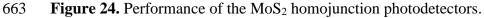
Figure 23. (a)-(c)Photodetectors based on graphene homo-junction and the photocurrent with
incident light. (d)MoS2 homojunction photodetector, (e)electrical properties of the devices
and (f) photocurrent generated with light illumination.

645

shown in Figure 24(d)-(f). Moreover, TMDs including WSe₂, WS₂, MoTe₂ et al. have been utilized in the photodetectors. [134] The photodetectors using 2D materials heterojunctions have also been investigated and optimized in many aspects, which are summarized in Ref. [135, 134, 136].

Lv et al. has also reported on the 2D photodetectors with MoS₂ homojunction. [122] Doping 653 654 in MoS₂ channel was reconfigurable by ferroelectric polarization. Polarization upward of 655 P(VDF-TrFE) with was applied as ferroelectric layer in the experiments due to its remarkable coercive field of $\sim 5 \times 10^7$ V m⁻¹. The MoS₂ channel turned into p-type semiconductor with 656 657 upward polarization and reversal of external electric field resulted in switch of majority carriers, as n-type doping were enhanced in the MoS₂ channel. 10^{9} - 10^{13} cm⁻² doping in MoS₂ 658 659 was achieved by ferroelectric polarization. It is noticed that voltage applied in polarization process varies with different channel materials (eg. $|V_p| < 10V$ with MoS₂ and $|Vp| = \pm 6$ V with 660 661 WSe₂).As shown in Figure 24, responsivity of the photodetector has reached up to 10^2 .





664 PN junctions based 2D-ferroelectrics hybrid structures are also studied, in which the 665 polarization of ferroelectrics could induce carrier transport of 2D materials. Responsivity of 666 the device was kept in the magnitude with UV spectrum, which confirmed the function of the 667 photodetector at UV region. Moreover, ferroelectrics applied in the photodetector could 668 effectively influence the device performance. [137]

In addition to the devices based on MoS₂ with ferroelectrics, similar researches have been 669 670 carried out with various materials. Wu et al has reported MoTe₂ PN junction defined by 671 ferroelectrics, as shown in Figure 25.[45] PN junction could be converted to n-p, n-n and p-p doping by external voltage pulses, as shown in Figure 25(b). Such modified photodetector 672 under illumination of different wavelengths including 520 nm and infrared was investigated 673 674 (see Figure 25(c) and Ref [45]). Other figures of merit including EQE and responsivity were studied as well and on/off ratio of 5×10^5 was achieved. The responsivity could reach 5 A W⁻¹, 675 detectivity was 3×10^{12} Jones as well as fast response time of 30 µs. Such PN junctions enable 676 677 photodetection unveiled opportunities for advanced nano photodetectors and realizing nextgeneration optoelectronic devices. 678

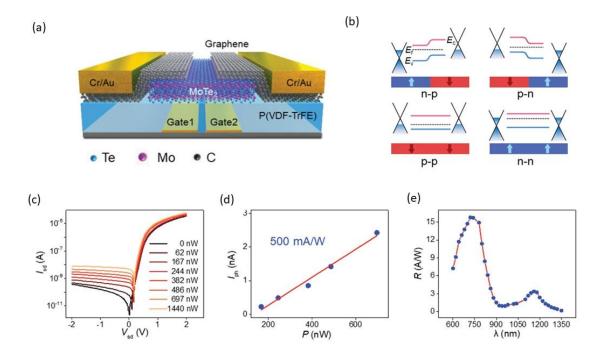


Figure 25. (a) MoTe2 PN junction controlled by ferroelectric domains. (b) switchable doping
method defined by polarization. (c)-(e) are devices performances under different illumination.

682 **3.4. Photodetectors based on field effect transistors**

679

683 Photodetectors based on 2D materials FETs with monolayer graphene as the channel were reported in 2008 for the first time. [138] Zero-bandgap graphene has the advantages of wide 684 685 band response, which allows facile generation of photocurrent by the incident light. Photocurrent of the graphene photodetector with 514.5 nm incident light reached a maximum 686 of ~350 nA with the gate bias varied in a relatively large range (-40 V-40 V), and the 687 688 photocurrent modulation by the gate bias was obviously observed in the devices, as shown in 689 Figure 26(a)-(c). Suspended graphene monolayer has high Fermi velocity (~1/300 of the speed of light in vacuum) and huge electrical mobility (200,000 cm²V⁻¹s⁻¹). Photocurrent of 690 691 the graphene FETs photodetectors has reached over 1 µA and the maximal responsivity was 0.5 mA W⁻¹. [28] For optical communication, the photoresponse in communication band is a 692 priority. Graphene has responsivity of 6.1 mA W⁻¹ at the wavelength of 1550 nm. Back gate 693 monolayer graphene photodetectors at a data rate of 10 Gbit s⁻¹ at 1550 nm incident light was 694 695 achieved, as shown in Figure 26(d)-(f).

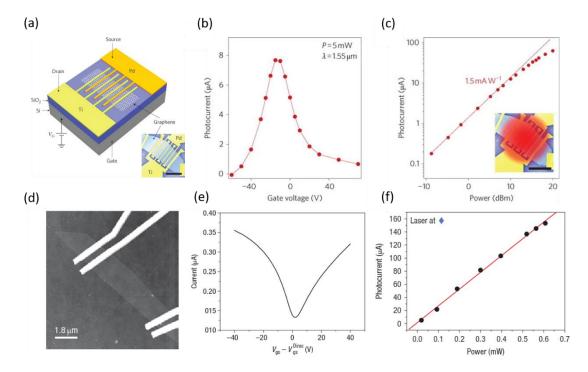


Figure 26. (a)-(c) is Graphene photodetectors where (a) is the structure of the devices, (b) and
(c) are the photocurrent dependent on the gate voltage and incident power intensity,
respectively.[138] (d)-(f) is Back gate monolayer graphene phototransistors enable high speed
photo communication.[28]

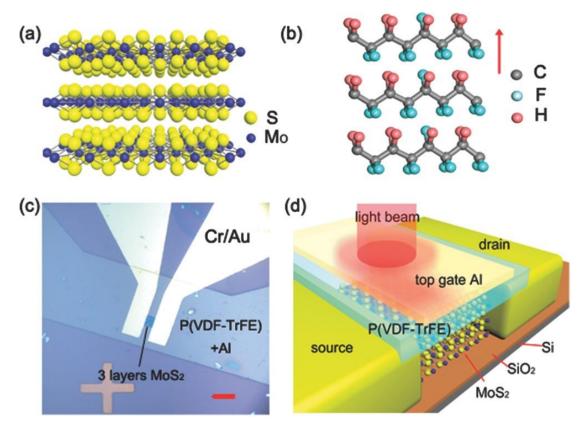
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701 Besides graphene other 2D materials, for instance the CNTs, TMDs and h-BN etc. have been 702 also applied in photodetection inspired by graphene FETs photodetectors. Similar MoS₂ 703 monolayer FET structures and devices have been reported, firstly by Yin et al. in 2011[129] 704 One of the most prominent properties of the MoS₂ different from graphene is that monolayer 705 MoS_2 has an intrinsic bandgap of 1.8 eV, which enables MoS_2 to be "switched off" in the FETs. However, the pristine MoS₂ has relatively low mobility ranging from $0.5 \text{ cm}^2 \text{V}^{-1} \text{s}^{-1}$ to 3 706 707 $cm^2V^{-1}s^{-1}$, [139] which could result in the impurity scattering and remote charge. High-k 708 dielectrics could be good in improving the transport properties which could provide charge 709 screening and reduce the trap/impurity scattering, then could consequently improve the carrier 710 mobility. Inorganic HfO₂ and Al₂O₃ are among the most studied dielectrics, for the organic 711 materials, PVDF is a typical material that was utilized as the gate insulator. The mobility of MoS₂ could be increased by two orders of magnitude, together with high on/off ratio of 10⁸ 712

and is thus very promising in the device applications [140]. In MoS₂ FET photodetectors, photocurrent is linearly proportional to the power of incident light High on/off ratio with ~10⁸ could be achieved by high-k dielectrics like PZT, HfO₂ and Al₂O₃. On/off ratio for the simple back gate monolayer MoS₂ with SiO₂ as gate insulator was measured to be 10^2 - 10^3 , and the delay was at ~50 ms. [129] The back gate monolayer MoS₂ FET was fabricated and the photoresponsivity was 7.5 mA/W with low power incident light (P=80 µW) and medium gate bias (V_g=50 V) [129].

FET Photodetectors based on TMDs, BP and h-BN with remarkable photoresponse has also been studied and shown. Improvement of the devices performance and novel phenomena were found and discussed. 2D material heterostructures was achieved to realize the photodetection [141]. More recently, many studies are devoting themselves to realize flexible and transparent photodetectors using 2D materials, which are of great interest for the future applications of wearable and solar-energy devices.

726 Photodetectors based on 2D materials modulated by ferroelectrics has been reported since 727 2015. Initially ferroelectrics were introduced to 2D FET photodetectors only thanks to their 728 high-k property, which can be used to enhance the photodetection performance. Wang et al. are among the first groups demonstrating MoS_2 based 2D photodetectors driven by 729 730 ferroelectric P(PVDF-TrFE) and they proposed the device structure as shown in in Figure 731 27.[142] Few layer MoS₂ was used as semiconducting channel while the P(VDF-TrFE) was 732 employed as the gate insulator. Dark current with non-polarized P(VDF-TrFE) was measured at 10^{-7} - 10^{-8} A and could be depressed to $<10^{-10}$ A with polarized-up P(VDF-TrFE). Signal-to-733 noise-ratio reached 10^3 using polarized gate. Illuminated by an incident light with a 734 735 wavelength of 635 nm, the photocurrent of the device reached $>50 \text{ }\mu\text{A}$ at a low power of 1nW 736 and 5 V source-drain voltage. Meanwhile, the stable polarization of P(VDF-TrFE) provided a high electric field (~ 10^9 V m⁻¹ within the nanometer scale) thus keeping the MoS₂ channel in 737 738 the fully depleted state, which significantly improved the sensitivity of the detector. The

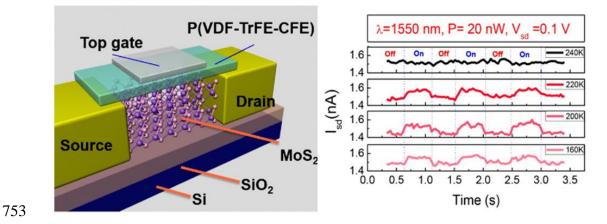


740 **Figure 27.** Ultra-sensitive MoS₂ photodetectors with ferroelectrics

739

741 photodetector reached quite a high detectivity $\sim 2.2 \times 10^{12}$ Jones and a responsivity up to 2570 742 A W⁻¹.

743 Similar 2D-ferroelectrics phototransistors have recently been extensively studied and 744 reported. Wide band photodetection (from visible light to 1550 nm) was achieved and the relative high sensitivity >340 A W⁻¹ was measured with an incident light wavelength of 745 746 450nm.[143] Considering that both the crystalline structure of ferroelectric gate materials and 747 the carrier transport fluctuation in the 2D materials strongly depend on the temperature 748 variation, the temperature dependence of the 2D-ferroelectrics hybrid FET photodetectors 749 have been studied. Chen et al. has reported that a low temperature of 200 K could transform 750 the lattice structure of P(VDF-TrFE-CFE) into ferroelectrics/relaxor, which changes the 751 property of P(VDF-TrFE) and could further modulate the band structure of the few-layer



752 MoS₂ material, enabling the long wavelength detection to 1550 nm, as shown in Figure

Figure 28. Schematic illustration of the MoS₂ photodetectors driven by ferroelectric gate and
the temperature dependence of the response at 1550 nm incident light.

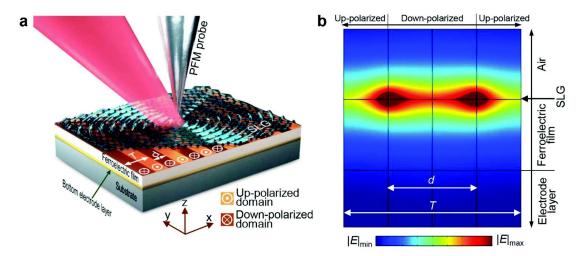
756 <u>28</u>.[143] Screening coulomb impurities of ferroelectrics could also enhance the carrier
 757 mobility of MoS₂.

758 On-off ratio and delay are another two key figures of merits of the 2D-ferroelectrics hybrid 759 photodetectors. On/off ratio of the devices was determined at zero gate bias at a low drain 760 currents, while delay time of the devices accounts for the time required to switch the device 761 on. Both on/off ratio and delay time express the response speed of the devices. On/off ratio for the monolayer MoS_2 based nano electronic devices could reach up to 10^8 [144]and the 762 763 simplest back gate FETs as photodetectors have an on/off ratio of 10^2 - 10^3 [145]. Application 764 of the ferroelectrics has been proved to be able to significantly improve the sensitivity, the 765 on/off ratio and the SNR of photodetector. On/off ratio of MoS2 photodetector with P(VDF-TrFE) applied as ferroelectric gate was increased to $>10^4$ with dark current approximately to 766 10⁻¹¹ A [146]. 767

In the 2D-ferroelectrics hybrid photodetectors, some unique properties of 2D materials, like the plasmonic behaviors of graphene, could be modulated by the ferroelectrics, which further improve the photodetection performances. An ultra-high responsivity up to 7.62×10^6 A W⁻¹ has been reported graphene-ferroelectrics photodetectors, which is much beyond the

previously reported experimental results. Meanwhile, detectivity reached $\sim 6.24 \times 10^7$ Jones with infra-red band photodetection. [147] Graphene was transferred on the pre-polarized ferroelectric substrate and the graphene plasmons was excited by the polarized domains. Graphene plasmons resonates at the boundaries, as shown in Figure 29. Polarized domains at the substrate could modulate the carrier density and the chemical potential (namely the Fermi level) of graphene by the external electric field. Broad band photodetector with wavelengths ranging from 5µm to20µm was achieved, as shown in Figure 30.

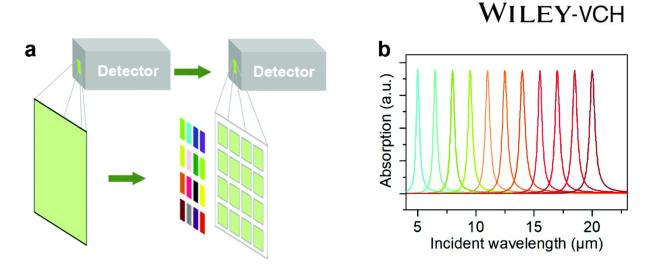
779 For the extensive investigation of 2D materials and ferroelectrics. There is a group of unique 780 2D semiconductors, represented by α -In₂Se₃, shares both semiconductor property and the 781 ferroelectricity. The combined properties make it potential in the ultra-thin photodetectors due 782 to its capability of playing a dual role in the application of photodetectors. Hou et al has 783 reported the α -In₂Se₃ applied in the photodetectors, as shown in Figure 31. [148] Polarization 784 of α -In₂Se₃ pull the electrons to the surface of the materials and consequently forms into an 785 electric field, which would influence the electrical properties of the photodetectors. On/off ratio of the photodetector was measured to be 2×10^7 and the comparison of the photodetector 786 787 with and without polarization demonstrated that the polarization could prolong the decay yet significantly improve the on/off ratio with even three orders of magnitude, and 788



789

790 Figure 29. pre-polarized graphene photodetector and the plasmons excited by the polarized-

up and -down domains



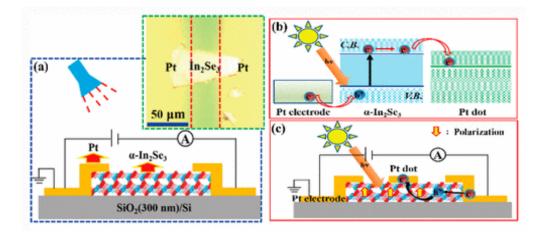
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Figure 30. Graphene plasmonic photodetector controlled by ferroelectric domains and thewide-band response

Photodetectors with Pt electrodes could further optimize the on/off ratio by four orders ofmagnitude.

In addition to traditional ferroelectrics, recent emerged ferroelectric semiconductors have also
attracted many interests and have been applied into 2D-ferroelectris hybrid photodetectors.

The ferroelectric TMD α -indium selenide (In₂Se₃) is one typical representative. Photodetectors based on WSe₂ and α - In₂Se₃ heterostructures have been reported in 2020. [149] and ultra-low dark current of 10⁻¹³ A was achieved, which is a remarkable result compared to photodetectors with the similar structure. Meanwhile, such device also has high on/off ratio exceeding 1.24×10⁵ and photoresponse of 26 mA W⁻¹. Liu *et al.* has also reported InSe2 photodetectors with P(VDF-TrFE) ferroelectric gate. [120] Different polarization of



805

806 **Figure 31.** Schematics of the α -In₂Se₃ photodetector.

P(VDF-TrFE) was studied to improve the performance of the photodetector. High on/off ratio 807 of 10^8 , fast response time of 600 µs and high photoresponsivity up to 14250 AW⁻¹ were 808 809 achieved. However, few researches were focused on the ferroelectricity of InSe materials. Xu 810 et al. as briefly reported the optoelectronic properties in WSe₂/In₂Se₃ heterostructures in 2018, 811 In₂Se₃ was polarized and the output properties in dark and under illumination was investigated, 812 as shown in Figure 32. Photocurrent was enhanced with positive voltage bias applied in gate 813 dielectrics. Enhancement and weaken of the photocurrent were able to be modulated by 814 varying the voltage bias from negative to positive, as shown in Figure 32(f). Photoresponse 815 was thus improved by ferroelectric modulation.

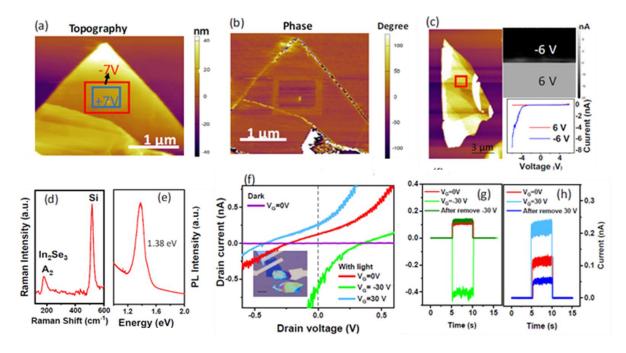


Figure 32. (a) Height image and (b) out-of-plane phase image of In_2Se_3 in PFM measurement. (c) Topography image, current mapping and local IV curves after writing with -6 V and 6 V in CAFM measurement. (d) Raman spectrum and (e) PL spectrum of a α -In₂Se₃ flake. (f) Photocurrent as a function of drain voltage of the photodetector based on WSe₂/In₂Se₃ heterostructure measured at various gate voltages. Inset: optical image of the device. (g) and (h) Short-circuit current as a function of time measured in a photodetector based on the WSe₂/In₂Se₃ heterostructure before, during, and after applied +30 V and -30 V gate voltages.

816

824 **4.** Conclusions and perspectives

In this review, we have reviewed the fundamentals of two-dimensional semiconductors and ferroelectrics as well as their application in photodetection. Hybrid system of twodimensional materials and ferroelectrics could interact with each other, and thus realize higher performances and enable modulation of the devices. This novel combination structure has provided new methods for multiple functional nano-devices and compatible circuits.

In materials aspect, structure, physical properties, electrical properties as well as
optoelectronic properties has been reviewed. Additionally, interaction between twodimensional materials and ferroelectrics has been introduced.

833 In devices aspect, photodetectors based on two-dimensional materials and ferroelectrics has 834 been categorized based on their structures and the performances as well as the interaction in 835 the hybrid system has been reviewed. Researches based on two-dimensional materials and 836 ferroelectrics have shown great potential in photodetectors. Remarkable achievements have 837 witnessed however, problems still exit. Considering the structure of the devices, most of the 838 researches focused on the field effect transistors with ferroelectrics as top gate, more work 839 still remains to be done in the study of the ferroelectric layer applied as bottom gate as well as 840 substrates. Meanwhile, photodetectors based on PN junctions are mostly based on the vertical heterojunctions with silicon as substrate or doped lateral junctions. Modulation of the carrier 841 842 type and the junction generated from ferroelectric polarization has not been fully investigated 843 either. Details and the mechanism of interaction between the two-dimensional semiconductor 844 and the functional ferroelectric layer is still unintelligible, which is currently a challenge for 845 the application of photodetectors based on 2D materials and ferroelectrics. As is mentioned 846 before that the 2D materials has outstanding flexibility and mechanical strength, the joint 847 ferroelectric substrates in the flexible devices are expecting to be flexible and transparent as 848 well. Therefore, more attention is required on designing and fabrication of ultrathin 849 ferroelectric film with high transparency and outstanding mechanical properties.

In conclusion, photodetectors based on two dimensional materials, ferroelectrics as well as the hybrid structures is promising structure for wide band high performance photodetection. Ferroelectric provide effective modulation of the devices and thus improve optical and optoelectronic properties of the devices. It is promising that the ferroelectric layer being applied as component of integrated circuit and will certainly lead to another prosperity area in exploring the road "More than Moore".

856

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